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Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e300
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	400MHz
Co-Processors/DSP	-
RAM Controllers	DDR
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (2)
SATA	-
USB	USB 2.0 + PHY (2)
Voltage - I/O	2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	672-LBGA
Supplier Device Package	672-LBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8347zuagdb

3 Power Characteristics

The estimated typical power dissipation for the MPC8347E device is shown in [Table 4](#).

Table 4. MPC8347E Power Dissipation¹

	Core Frequency (MHz)	CSB Frequency (MHz)	Typical at $T_J = 65$	Typical ^{2,3}	Maximum ⁴	Unit
PBGA	266	266	1.3	1.6	1.8	W
		133	1.1	1.4	1.6	W
	400	266	1.5	1.9	2.1	W
		133	1.4	1.7	1.9	W
	400	200	1.5	1.8	2.0	W
		100	1.3	1.7	1.9	W
TBGA	333	333	2.0	3.0	3.2	W
		166	1.8	2.8	2.9	W
	400	266	2.1	3.0	3.3	W
		133	1.9	2.9	3.1	W
	450	300	2.3	3.2	3.5	W
		150	2.1	3.0	3.2	W
	500	333	2.4	3.3	3.6	W
		166	2.2	3.1	3.4	W
	533	266	2.4	3.3	3.6	W
		133	2.2	3.1	3.4	W

¹ The values do not include I/O supply power (OV_{DD} , LV_{DD} , GV_{DD}) or AV_{DD} . For I/O power values, see [Table 5](#).

² Typical power is based on a voltage of $V_{DD} = 1.2$ V, a junction temperature of $T_J = 105^\circ\text{C}$, and a Dhystone benchmark application.

³ Thermal solutions may need to design to a value higher than typical power based on the end application, T_A target, and I/O power.

⁴ Maximum power is based on a voltage of $V_{DD} = 1.2$ V, worst case process, a junction temperature of $T_J = 105^\circ\text{C}$, and an artificial smoke test.

Table 9. RESET Initialization Timing Specifications (continued)

Parameter/Condition	Min	Max	Unit	Notes
Input hold time for POR configuration signals with respect to negation of $\overline{\text{HRESET}}$	0	—	ns	
Time for the MPC8347E to turn off POR configuration signals with respect to the assertion of $\overline{\text{HRESET}}$	—	4	ns	3
Time for the MPC8347E to turn on POR configuration signals with respect to the negation of $\overline{\text{HRESET}}$	1	—	$t_{\text{PCI_SYNC_IN}}$	1, 3

Notes:

1. $t_{\text{PCI_SYNC_IN}}$ is the clock period of the input clock applied to PCI_SYNC_IN. In PCI host mode, the primary clock is applied to the CLKIN input, and PCI_SYNC_IN period depends on the value of CFG_CLKIN_DIV. See the *MPC8349E PowerQUICC™ II Pro Integrated Host Processor Family Reference Manual*.
2. t_{CLKIN} is the clock period of the input clock applied to CLKIN. It is valid only in PCI host mode. See the *MPC8349E PowerQUICC™ II Pro Integrated Host Processor Family Reference Manual*.
3. POR configuration signals consist of CFG_RESET_SOURCE[0:2] and CFG_CLKIN_DIV.

Table 10 lists the PLL and DLL lock times.

Table 10. PLL and DLL Lock Times

Parameter/Condition	Min	Max	Unit	Notes
PLL lock times	—	100	μs	
DLL lock times	7680	122,880	csb_clk cycles	1, 2

Notes:

1. DLL lock times are a function of the ratio between the output clock and the coherency system bus clock (csb_clk). A 2:1 ratio results in the minimum and an 8:1 ratio results in the maximum.
2. The csb_clk is determined by the CLKIN and system PLL ratio. See Section 19, “Clocking.”

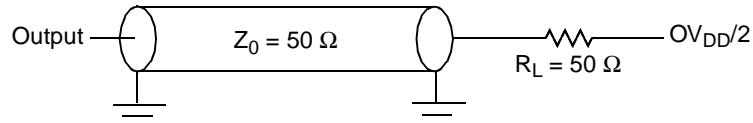


Figure 6. DDR AC Test Load

Table 15 shows the DDR SDRAM measurement conditions.

Table 15. DDR SDRAM Measurement Conditions

Symbol	DDR	Unit	Notes
V_{TH}	$MV_{REF} \pm 0.31$ V	V	1
V_{OUT}	$0.5 \times GV_{DD}$	V	2

Notes:

1. Data input threshold measurement point.
2. Data output measurement point.

Figure 7 shows the DDR SDRAM output timing diagram for source synchronous mode.

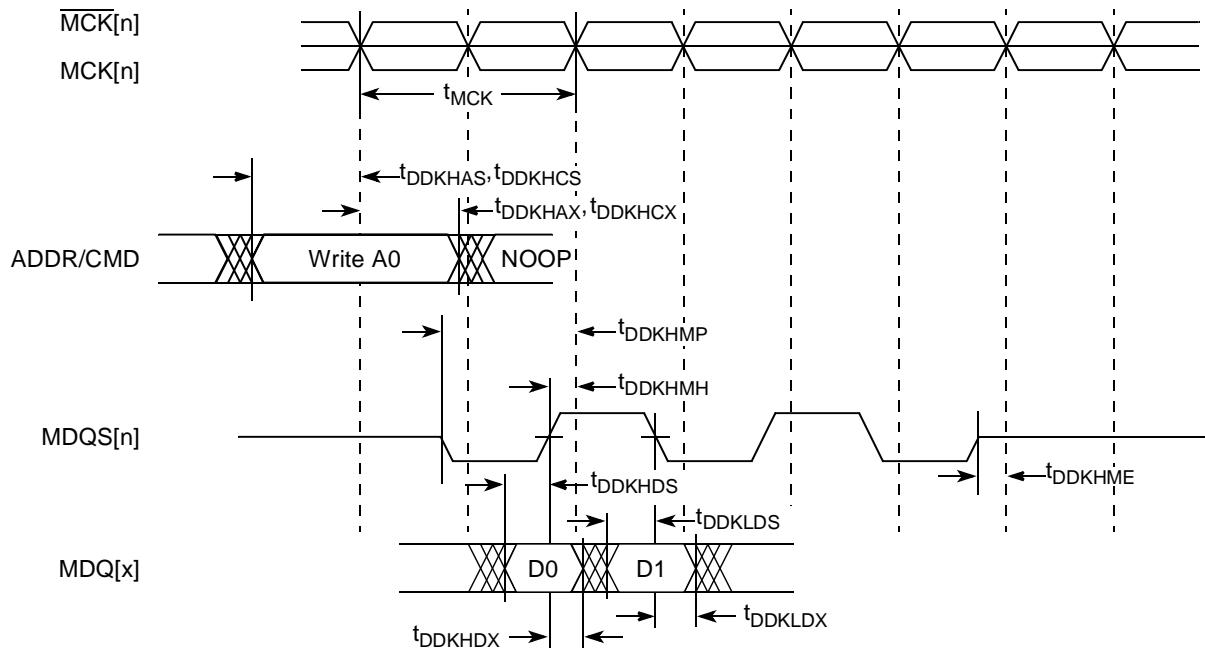


Figure 7. DDR SDRAM Output Timing Diagram for Source Synchronous Mode

Table 16 provides approximate delay information that can be expected for the address and command signals of the DDR controller for various loadings, which can be useful for a system utilizing the DLL. These numbers are the result of simulations for one topology. The delay numbers will strongly depend on the topology used. These delay numbers show the total delay for the address and command to arrive at the DRAM devices. The actual delay could be different than the delays seen in simulation, depending on the system topology. If a heavily loaded system is used, the DLL loop may need to be adjusted to meet setup requirements at the DRAM.

Figure 8 shows the GMII transmit AC timing diagram.

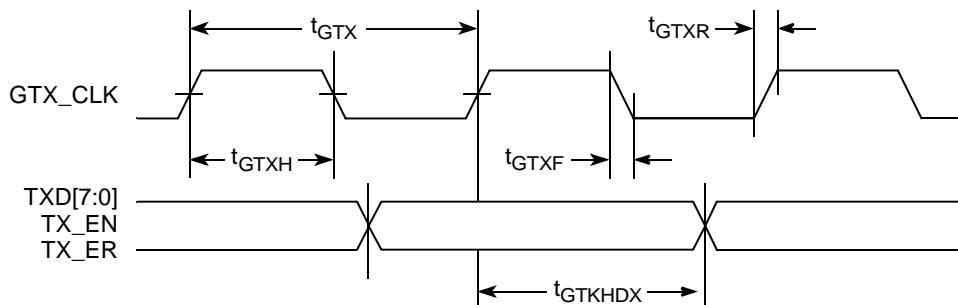


Figure 8. GMII Transmit AC Timing Diagram

8.2.1.2 GMII Receive AC Timing Specifications

Table 22 provides the GMII receive AC timing specifications.

Table 22. GMII Receive AC Timing Specifications

At recommended operating conditions with LV_{DD}/OV_{DD} of $3.3\text{ V} \pm 10\%$.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
RX_CLK clock period	t_{GRX}	—	8.0	—	ns
RX_CLK duty cycle	t_{GRXH}/t_{GRX}	40	—	60	%
RXD[7:0], RX_DV, RX_ER setup time to RX_CLK	t_{GRDVKH}	2.0	—	—	ns
RXD[7:0], RX_DV, RX_ER hold time to RX_CLK	t_{GRDXKH}	0.5	—	—	ns
RX_CLK clock rise, $V_{IL}(\text{min})$ to $V_{IH}(\text{max})$	t_{GRXR}	—	—	1.0	ns
RX_CLK clock fall time, $V_{IH}(\text{max})$ to $V_{IL}(\text{min})$	t_{GRXF}	—	—	1.0	ns

Note:

1. The symbols for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, t_{GRDVKH} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) reaching the valid state (V) relative to the t_{RX} clock reference (K) going to the high state (H) or setup time. Also, t_{GRDXKL} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{GRX} clock reference (K) going to the low (L) state or hold time. In general, the clock reference symbol is based on three letters representing the clock of a particular function. For example, the subscript of t_{GRX} represents the GMII (G) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

Figure 10 shows the MII transmit AC timing diagram.

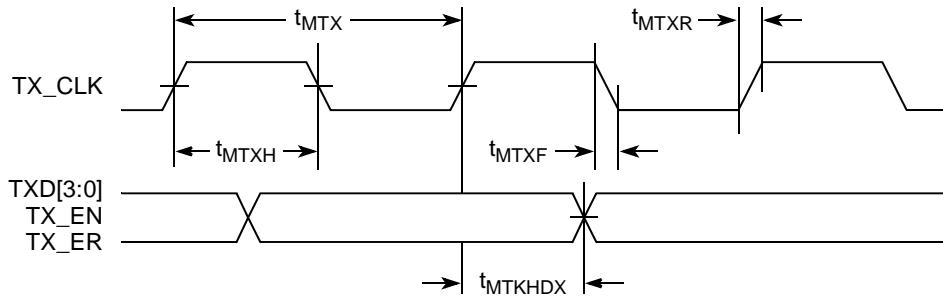


Figure 10. MII Transmit AC Timing Diagram

8.2.2.2 MII Receive AC Timing Specifications

Table 24 provides the MII receive AC timing specifications.

Table 24. MII Receive AC Timing Specifications

At recommended operating conditions with LV_{DD}/OV_{DD} of 3.3 V \pm 10%.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
RX_CLK clock period 10 Mbps	t_{MRX}	—	400	—	ns
RX_CLK clock period 100 Mbps	t_{MRX}	—	40	—	ns
RX_CLK duty cycle	t_{MRXH}/t_{MRX}	35	—	65	%
RXD[3:0], RX_DV, RX_ER setup time to RX_CLK	t_{MRDVKH}	10.0	—	—	ns
RXD[3:0], RX_DV, RX_ER hold time to RX_CLK	t_{MRDXKH}	10.0	—	—	ns
RX_CLK clock rise V_{IL} (min) to V_{IH} (max)	t_{MRXR}	1.0	—	4.0	ns
RX_CLK clock fall time V_{IH} (max) to V_{IL} (min)	t_{MRXF}	1.0	—	4.0	ns

Note:

1. The symbols for timing specifications follow the pattern of $t_{(first\ two\ letters\ of\ functional\ block)(signal)(state)(reference)(state)}$ for inputs and $t_{(first\ two\ letters\ of\ functional\ block)(reference)(state)(signal)(state)}$ for outputs. For example, t_{MRDVKH} symbolizes MII receive timing (MR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MRX} clock reference (K) going to the high (H) state or setup time. Also, t_{MRDXKL} symbolizes MII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{MRX} clock reference (K) going to the low (L) state or hold time. In general, the clock reference symbol is based on three letters representing the clock of a particular function. For example, the subscript of t_{MRX} represents the MII (M) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

Figure 11 provides the AC test load for TSEC.

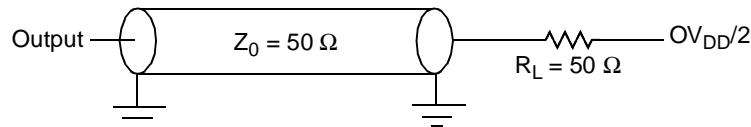


Figure 11. TSEC AC Test Load

8.3.2 MII Management AC Electrical Specifications

Table 30 provides the MII management AC timing specifications.

Table 30. MII Management AC Timing Specifications

At recommended operating conditions with LV_{DD} is $3.3\text{ V} \pm 10\%$ or $2.5\text{ V} \pm 5\%$.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit	Notes
MDC frequency	f_{MDC}	—	2.5	—	MHz	2
MDC period	t_{MDC}	—	400	—	ns	
MDC clock pulse width high	t_{MDCH}	32	—	—	ns	
MDC to MDIO delay	t_{MDKHDX}	10	—	170	ns	3
MDIO to MDC setup time	t_{MDDVKH}	5	—	—	ns	
MDIO to MDC hold time	t_{MDDXKH}	0	—	—	ns	
MDC rise time	t_{MDCR}	—	—	10	ns	
MDC fall time	t_{MDHF}	—	—	10	ns	

Notes:

1. The symbols for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, t_{MDKHDX} symbolizes management data timing (MD) for the time t_{MDC} from clock reference (K) high (H) until data outputs (D) are invalid (X) or data hold time. Also, t_{MDDVKH} symbolizes management data timing (MD) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MDC} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. This parameter is dependent on the csb_clk speed (that is, for a csb_clk of 267 MHz, the maximum frequency is 8.3 MHz and the minimum frequency is 1.2 MHz; for a csb_clk of 375 MHz, the maximum frequency is 11.7 MHz and the minimum frequency is 1.7 MHz).
3. This parameter is dependent on the csb_clk speed (that is, for a csb_clk of 267 MHz, the delay is 70 ns and for a csb_clk of 333 MHz, the delay is 58 ns).

Figure 16 shows the MII management AC timing diagram.

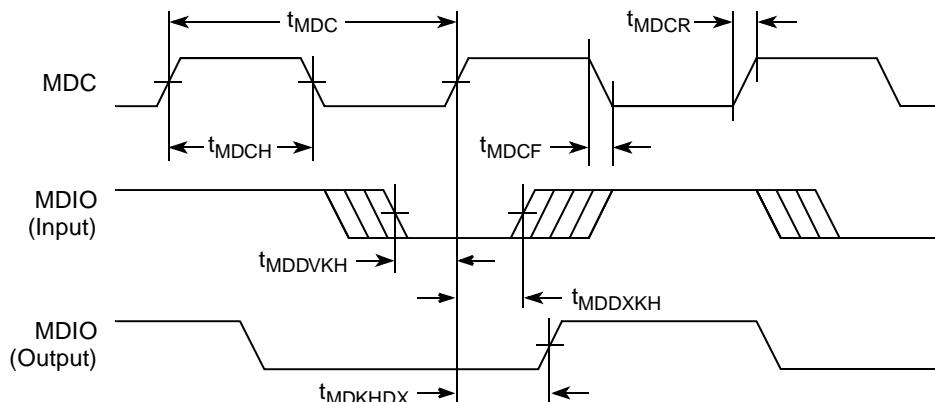


Figure 16. MII Management Interface Timing Diagram

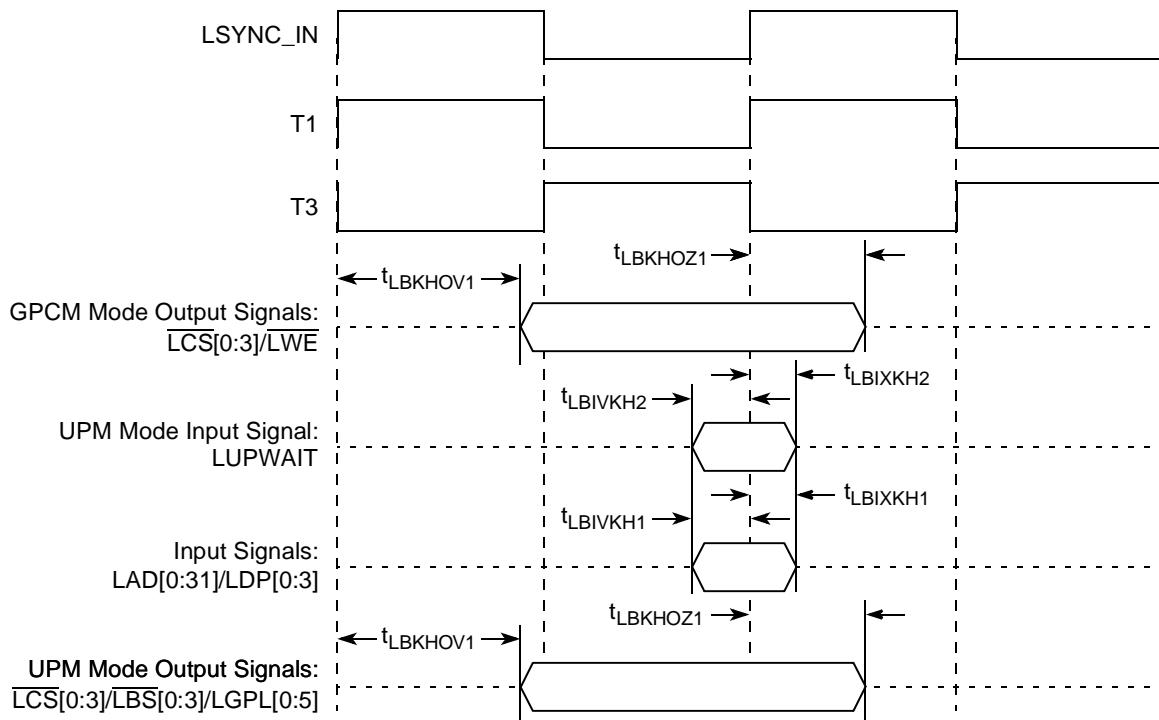


Figure 22. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 2 (DLL Enabled)

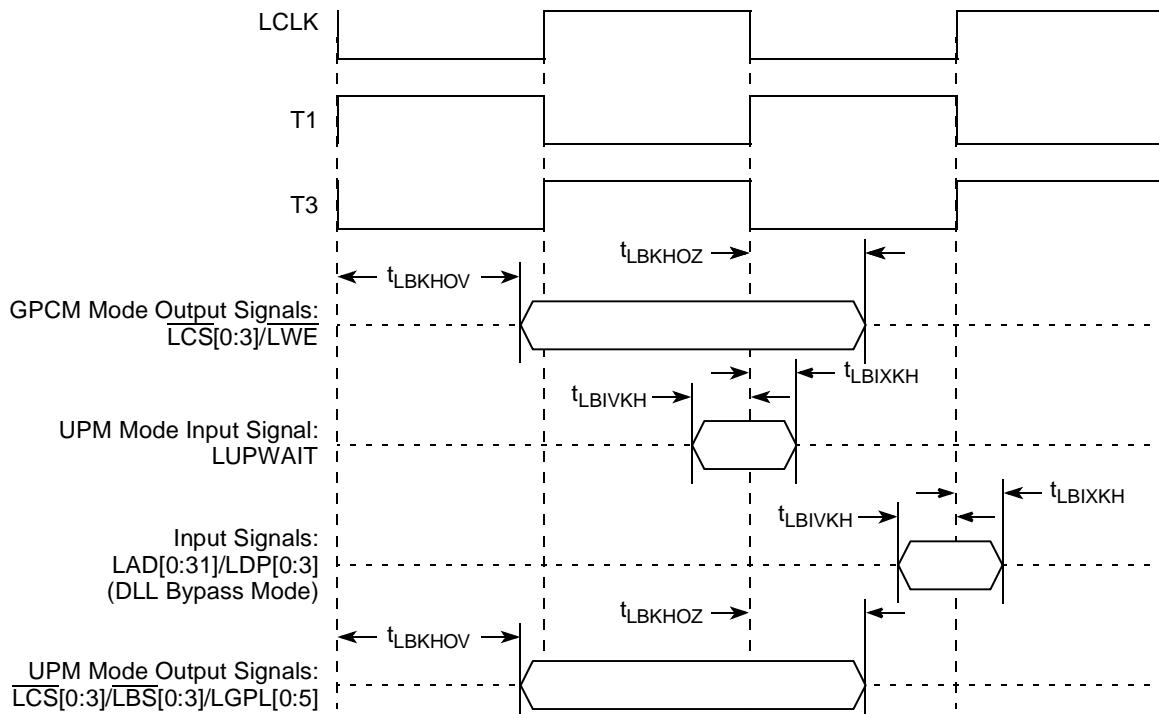


Figure 23. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 2 (DLL Bypass Mode)

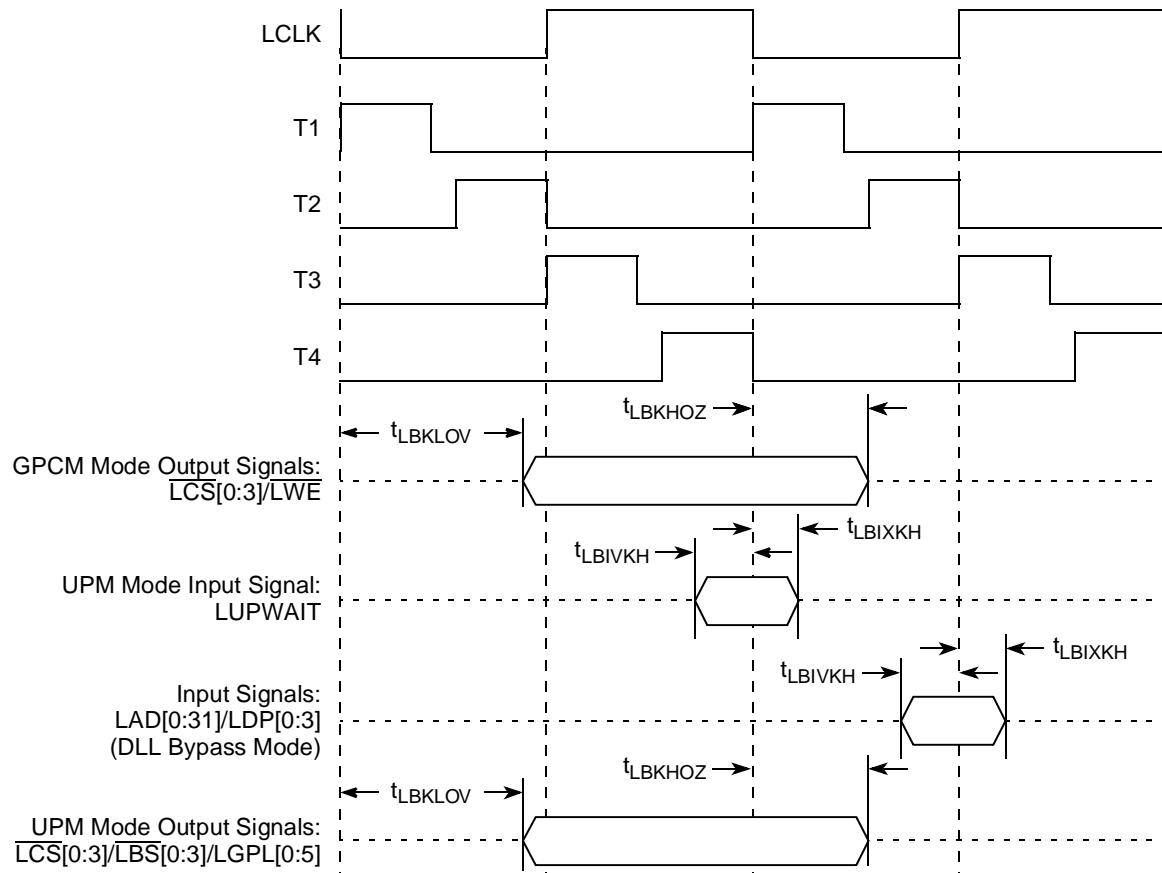


Figure 24. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 4 (DLL Bypass Mode)

Table 51. MPC8347E (TBGA) Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
LBCTL	AN26	O	OV _{DD}	
LALE	AK24	O	OV _{DD}	
LGPL0/LSDA10/cfg_reset_source0	AP27	I/O	OV _{DD}	
LGPL1/LSDWE/cfg_reset_source1	AL25	I/O	OV _{DD}	
LGPL2/LSDRAS/LOE	AJ24	O	OV _{DD}	
LGPL3/LSDCAS/cfg_reset_source2	AN27	I/O	OV _{DD}	
LGPL4/LGTA/LUPWAIT/LPBSE	AP28	I/O	OV _{DD}	
LGPL5/cfg_clkin_div	AL26	I/O	OV _{DD}	
LCKE	AM27	O	OV _{DD}	
LCLK[0:2]	AN28, AK26, AP29	O	OV _{DD}	
LSYNC_OUT	AM12	O	OV _{DD}	
LSYNC_IN	AJ10	I	OV _{DD}	
General Purpose I/O Timers				
GPIO1[0]/GTM1_TIN1/GTM2_TIN2	F24	I/O	OV _{DD}	
GPIO1[1]/GTM1_TGATE1/GTM2_TGATE2	E24	I/O	OV _{DD}	
GPIO1[2]/GTM1_TOUT1	B25	I/O	OV _{DD}	
GPIO1[3]/GTM1_TIN2/GTM2_TIN1	D24	I/O	OV _{DD}	
GPIO1[4]/GTM1_TGATE2/GTM2_TGATE1	A25	I/O	OV _{DD}	
GPIO1[5]/GTM1_TOUT2/GTM2_TOUT1	B24	I/O	OV _{DD}	
GPIO1[6]/GTM1_TIN3/GTM2_TIN4	A24	I/O	OV _{DD}	
GPIO1[7]/GTM1_TGATE3/GTM2_TGATE4	D23	I/O	OV _{DD}	
GPIO1[8]/GTM1_TOUT3	B23	I/O	OV _{DD}	
GPIO1[9]/GTM1_TIN4/GTM2_TIN3	A23	I/O	OV _{DD}	
GPIO1[10]/GTM1_TGATE4/GTM2_TGATE3	F22	I/O	OV _{DD}	
GPIO1[11]/GTM1_TOUT4/GTM2_TOUT3	E22	I/O	OV _{DD}	
USB Port 1				
MPH1_D0_ENABLEN/DR_D0_ENABLEN	A26	I/O	OV _{DD}	
MPH1_D1_SER_RXD/DR_D1_SER_RXD	B26	I/O	OV _{DD}	
MPH1_D2_VMO_SE0/DR_D2_VMO_SE0	D25	I/O	OV _{DD}	
MPH1_D3_SPEED/DR_D3_SPEED	A27	I/O	OV _{DD}	
MPH1_D4_DP/DR_D4_DP	B27	I/O	OV _{DD}	
MPH1_D5_DM/DR_D5_DM	C27	I/O	OV _{DD}	
MPH1_D6_SER_RCV/DR_D6_SER_RCV	D26	I/O	OV _{DD}	
MPH1_D7_DRVVBUS/DR_D7_DRVVBUS	E26	I/O	OV _{DD}	

Table 51. MPC8347E (TBGA) Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
Gigabit Reference Clock				
EC_GTX_CLK125	C8	I	LV _{DD1}	
Three-Speed Ethernet Controller (Gigabit Ethernet 1)				
TSEC1_COL/GPIO2[20]	A17	I/O	OV _{DD}	
TSEC1_CRS/GPIO2[21]	F12	I/O	LV _{DD1}	
TSEC1_GTX_CLK	D10	O	LV _{DD1}	3
TSEC1_RX_CLK	A11	I	LV _{DD1}	
TSEC1_RX_DV	B11	I	LV _{DD1}	
TSEC1_RX_ER/GPIO2[26]	B17	I/O	OV _{DD}	
TSEC1_RXD[7:4]/GPIO2[22:25]	B16, D16, E16, F16	I/O	OV _{DD}	
TSEC1_RXD[3:0]	E10, A8, F10, B8	I	LV _{DD1}	
TSEC1_TX_CLK	D17	I	OV _{DD}	
TSEC1_TXD[7:4]/GPIO2[27:30]	A15, B15, A14, B14	I/O	OV _{DD}	
TSEC1_TXD[3:0]	A10, E11, B10, A9	O	LV _{DD1}	11
TSEC1_TX_EN	B9	O	LV _{DD1}	
TSEC1_TX_ER/GPIO2[31]	A16	I/O	OV _{DD}	
Three-Speed Ethernet Controller (Gigabit Ethernet 2)				
TSEC2_COL/GPIO1[21]	C14	I/O	OV _{DD}	
TSEC2_CRS/GPIO1[22]	D6	I/O	LV _{DD2}	
TSEC2_GTX_CLK	A4	O	LV _{DD2}	
TSEC2_RX_CLK	B4	I	LV _{DD2}	
TSEC2_RX_DV/GPIO1[23]	E6	I/O	LV _{DD2}	
TSEC2_RXD[7:4]/GPIO1[26:29]	A13, B13, C13, A12	I/O	OV _{DD}	
TSEC2_RXD[3:0]/GPIO1[13:16]	D7, A6, E8, B7	I/O	LV _{DD2}	
TSEC2_RX_ER/GPIO1[25]	D14	I/O	OV _{DD}	
TSEC2_TXD[7]/GPIO1[31]	B12	I/O	OV _{DD}	
TSEC2_TXD[6]/DR_XCVR_TERM_SEL	C12	O	OV _{DD}	
TSEC2_TXD[5]/DR_UTMI_OPMODE1	D12	O	OV _{DD}	
TSEC2_TXD[4]/DR_UTMI_OPMODE0	E12	O	OV _{DD}	
TSEC2_TXD[3:0]/GPIO1[17:20]	B5, A5, F8, B6	I/O	LV _{DD2}	
TSEC2_TX_ER/GPIO1[24]	F14	I/O	OV _{DD}	
TSEC2_TX_EN/GPIO1[12]	C5	I/O	LV _{DD2}	3
TSEC2_TX_CLK/GPIO1[30]	E14	I/O	OV _{DD}	

Table 51. MPC8347E (TBGA) Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
DUART				
UART_SOUT[1:2]/MSRCID[0:1]/LSRCID[0:1]	AK27, AN29	O	OV _{DD}	
UART_SIN[1:2]/MSRCID[2:3]/LSRCID[2:3]	AL28, AM29	I/O	OV _{DD}	
UART_CTS[1]/MSRCID4/LSRCID4	AP30	I/O	OV _{DD}	
UART_CTS[2]/MDVAL/ LDVAL	AN30	I/O	OV _{DD}	
UART_RTS[1:2]	AP31, AM30	O	OV _{DD}	
I²C interface				
IIC1_SDA	AK29	I/O	OV _{DD}	2
IIC1_SCL	AP32	I/O	OV _{DD}	2
IIC2_SDA	AN31	I/O	OV _{DD}	2
IIC2_SCL	AM31	I/O	OV _{DD}	2
SPI				
SPIMOSI	AN32	I/O	OV _{DD}	
SPIMISO	AP33	I/O	OV _{DD}	
SPICLK	AK30	I/O	OV _{DD}	
SPISEL	AL31	I	OV _{DD}	
Clocks				
PCI_CLK_OUT[0:4]	AN9, AP9, AM10, AN10, AJ11	O	OV _{DD}	
PCI_SYNC_IN/PCI_CLOCK	AK12	I	OV _{DD}	
PCI_SYNC_OUT	AP11	O	OV _{DD}	3
RTC/PIT_CLOCK	AM32	I	OV _{DD}	
CLKIN	AM9	I	OV _{DD}	
JTAG				
TCK	E20	I	OV _{DD}	
TDI	F20	I	OV _{DD}	4
TDO	B20	O	OV _{DD}	3
TMS	A20	I	OV _{DD}	4
TRST	B19	I	OV _{DD}	4
Test				
TEST	D22	I	OV _{DD}	6
TEST_SEL	AL13	I	OV _{DD}	7
PMC				
QUIESCE	A18	O	OV _{DD}	

Table 52. MPC8347E (PBGA) Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
MCAS	AG6	O	GV _{DD}	
MCS[0:3]	AE7, AH7, AH4, AF2	O	GV _{DD}	
MCKE[0:1]	AG23, AH23	O	GV _{DD}	3
MCK[0:5]	AH15, AE24, AE2, AF14, AE23, AD3	O	GV _{DD}	
MCK[0:5]	AG15, AD23, AE3, AG14, AF24, AD2	O	GV _{DD}	
Pins Reserved for Future DDR2 (They should be left unconnected for MPC8347)				
MODT[0:3]	AG5, AD4, AH6, AF4	—	—	
MBA[2]	AD22	—	—	
SPARE1	AF12	—	—	7
SPARE2	AG11	—	—	6
Local Bus Controller Interface				
LAD[0:31]	T4, T5, T1, R2, R3, T2, R1, R4, P1, P2, P3, P4, N1, N4, N2, N3, M1, M2, M3, N5, M4, L1, L2, L3, K1, M5, K2, K3, J1, J2, L5, J3	I/O	OV _{DD}	
LDP[0]/CKSTOP_OUT	H1	I/O	OV _{DD}	
LDP[1]/CKSTOP_IN	K5	I/O	OV _{DD}	
LDP[2]	H2	I/O	OV _{DD}	
LDP[3]	G1	I/O	OV _{DD}	
LA[27:31]	J4, H3, G2, F1, G3	O	OV _{DD}	
LCS[0:3]	J5, H4, F2, E1	O	OV _{DD}	
LWE[0:3]/LSDDQM[0:3]/LBS[0:3]	F3, G4, D1, E2	O	OV _{DD}	
LBCTL	H5	O	OV _{DD}	
LALE	E3	O	OV _{DD}	
LGPL0/LSDA10/cfg_reset_source0	F4	I/O	OV _{DD}	
LGPL1/LSDWE/cfg_reset_source1	D2	I/O	OV _{DD}	
LGPL2/LSDRAS/LOE	C1	O	OV _{DD}	
LGPL3/LSDCAS/cfg_reset_source2	C2	I/O	OV _{DD}	
LGPL4/LGTA/LUPWAIT/LPBSE	C3	I/O	OV _{DD}	
LGPL5/cfg_clkin_div	B3	I/O	OV _{DD}	
LCKE	E4	O	OV _{DD}	
LCLK[0:2]	D4, A3, C4	O	OV _{DD}	
LSYNC_OUT	U3	O	OV _{DD}	
LSYNC_IN	Y2	I	OV _{DD}	

Table 52. MPC8347E (PBGA) Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
General Purpose I/O Timers				
GPIO1[0]/GTM1_TIN1/GTM2_TIN2	D27	I/O	OV _{DD}	
GPIO1[1]/GTM1_TGATE1/GTM2_TGATE2	E26	I/O	OV _{DD}	
GPIO1[2]/GTM1_TOUT1	D28	I/O	OV _{DD}	
GPIO1[3]/GTM1_TIN2/GTM2_TIN1	G25	I/O	OV _{DD}	
GPIO1[4]/GTM1_TGATE2/GTM2_TGATE1	J24	I/O	OV _{DD}	
GPIO1[5]/GTM1_TOUT2/GTM2_TOUT1	F26	I/O	OV _{DD}	
GPIO1[6]/GTM1_TIN3/GTM2_TIN4	E27	I/O	OV _{DD}	
GPIO1[7]/GTM1_TGATE3/GTM2_TGATE4	E28	I/O	OV _{DD}	
GPIO1[8]/GTM1_TOUT3	H25	I/O	OV _{DD}	
GPIO1[9]/GTM1_TIN4/GTM2_TIN3	F27	I/O	OV _{DD}	
GPIO1[10]/GTM1_TGATE4/GTM2_TGATE3	K24	I/O	OV _{DD}	
GPIO1[11]/GTM1_TOUT4/GTM2_TOUT3	G26	I/O	OV _{DD}	
USB Port 1				
MPH1_D0_ENABLEN/DR_D0_ENABLEN	C28	I/O	OV _{DD}	
MPH1_D1_SER_RXD/DR_D1_SER_RXD	F25	I/O	OV _{DD}	
MPH1_D2_VMO_SE0/DR_D2_VMO_SE0	B28	I/O	OV _{DD}	
MPH1_D3_SPEED/DR_D3_SPEED	C27	I/O	OV _{DD}	
MPH1_D4_DP/DR_D4_DP	D26	I/O	OV _{DD}	
MPH1_D5_DM/DR_D5_DM	E25	I/O	OV _{DD}	
MPH1_D6_SER_RCV/DR_D6_SER_RCV	C26	I/O	OV _{DD}	
MPH1_D7_DRVVBUS/DR_D7_DRVVBUS	D25	I/O	OV _{DD}	
MPH1_NXT/DR_SESS_VLD_NXT	B26	I	OV _{DD}	
MPH1_DIR_DPPULLUP/ DR_XCVR_SEL_DPPULLUP	E24	I/O	OV _{DD}	
MPH1_STP_SUSPEND/ DR_STP_SUSPEND	A27	O	OV _{DD}	
MPH1_PWRFAULT/ DR_RX_ERROR_PWRFAULT	C25	I	OV _{DD}	
MPH1_PCTL0/DR_TX_VALID_PCTL0	A26	O	OV _{DD}	
MPH1_PCTL1/DR_TX_VALIDH_PCTL1	B25	O	OV _{DD}	
MPH1_CLK/DR_CLK	A25	I	OV _{DD}	
USB Port 0				
MPH0_D0_ENABLEN/DR_D8_CHGVBUS	D24	I/O	OV _{DD}	
MPH0_D1_SER_RXD/DR_D9_DCHGVBUS	C24	I/O	OV _{DD}	

Table 52. MPC8347E (PBGA) Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
AV _{DD3}	AF9	Power for DDR DLL (1.2 V)	AV _{DD3}	
AV _{DD4}	U2	Power for LBIU DLL (1.2 V)	AV _{DD4}	
GND	A2, B1, B2, D10, D18, E6, E14, E22, F9, F12, F15, F18, F21, F24, G5, H6, J23, L4, L6, L12, L13, L14, L15, L16, L17, M11, M12, M13, M14, M15, M16, M17, M18, M23, N11, N12, N13, N14, N15, N16, N17, N18, P6, P11, P12, P13, P14, P15, P16, P17, P18, P24, R5, R11, R12, R13, R14, R15, R16, R17, R18, R23, T11, T12, T13, T14, T15, T16, T17, T18, U6, U11, U12, U13, U14, U15, U16, U17, U18, V12, V13, V14, V15, V16, V17, V23, V25, W4, Y6, AA23, AB24, AC5, AC8, AC11, AC14, AC17, AC20, AD9, AD15, AD21, AE12, AE18, AF3, AF26	—	—	
GV _{DD}	U9, V9, W10, W19, Y11, Y12, Y14, Y15, Y17, Y18, AA6, AB5, AC9, AC12, AC15, AC18, AC21, AC24, AD6, AD8, AD14, AD20, AE5, AE11, AE17, AG2, AG27	Power for DDR DRAM I/O voltage (2.5 V)	GV _{DD}	
LV _{DD1}	U20, W25	Power for three-speed Ethernet #1 and for Ethernet management interface I/O (2.5 V, 3.3 V)	LV _{DD1}	
LV _{DD2}	V20, Y23	Power for three-speed Ethernet #2 I/O (2.5 V, 3.3 V)	LV _{DD2}	
V _{DD}	J11, J12, J15, K10, K11, K12, K13, K14, K15, K16, K17, K18, K19, L10, L11, L18, L19, M10, M19, N10, N19, P9, P10, P19, R10, R19, R20, T10, T19, U10, U19, V10, V11, V18, V19, W11, W12, W13, W14, W15, W16, W17, W18	Power for core (1.2 V)	V _{DD}	
OV _{DD}	B27, D3, D11, D19, E15, E23, F5, F8, F11, F14, F17, F20, G24, H23, H24, J6, J14, J17, J18, K4, L9, L20, L23, L25, M6, M9, M20, P5, P20, P23, R6, R9, R24, U23, V4, V6	PCI, 10/100 Ethernet, and other standard (3.3 V)	OV _{DD}	

As shown in [Figure 41](#), the primary clock input (frequency) is multiplied up by the system phase-locked loop (PLL) and the clock unit to create the coherent system bus clock (*csb_clk*), the internal clock for the DDR controller (*ddr_clk*), and the internal clock for the local bus interface unit (*lbiu_clk*).

The *csb_clk* frequency is derived from a complex set of factors that can be simplified into the following equation:

$$csb_clk = \{PCI_SYNC_IN \times (1 + CFG_CLKIN_DIV)\} \times SPMF$$

In PCI host mode, *PCI_SYNC_IN* \times $(1 + CFG_CLKIN_DIV)$ is the CLKIN frequency.

The *csb_clk* serves as the clock input to the e300 core. A second PLL inside the e300 core multiplies the *csb_clk* frequency to create the internal clock for the e300 core (*core_clk*). The system and core PLL multipliers are selected by the SPMF and COREPLL fields in the reset configuration word low (RCWL), which is loaded at power-on reset or by one of the hard-coded reset options. See the chapter on reset, clocking, and initialization in the *MPC8349E Reference Manual* for more information on the clock subsystem.

The internal *ddr_clk* frequency is determined by the following equation:

$$ddr_clk = csb_clk \times (1 + RCWL[DDRCM])$$

ddr_clk is not the external memory bus frequency; *ddr_clk* passes through the DDR clock divider ($\div 2$) to create the differential DDR memory bus clock outputs (MCK and \overline{MCK}). However, the data rate is the same frequency as *ddr_clk*.

The internal *lbiu_clk* frequency is determined by the following equation:

$$lbiu_clk = csb_clk \times (1 + RCWL[LBIUCM])$$

lbiu_clk is not the external local bus frequency; *lbiu_clk* passes through the LBIU clock divider to create the external local bus clock outputs (LSYNC_OUT and LCLK[0:2]). The LBIU clock divider ratio is controlled by LCCR[CLKDIV].

In addition, some of the internal units may have to be shut off or operate at lower frequency than the *csb_clk* frequency. Those units have a default clock ratio that can be configured by a memory-mapped register after the device exits reset. [Table 53](#) specifies which units have a configurable clock frequency.

Table 53. Configurable Clock Units

Unit	Default Frequency	Options
TSEC1	<i>csb_clk/3</i>	Off, <i>csb_clk</i> , <i>csb_clk/2</i> , <i>csb_clk/3</i>
TSEC2, I ² C1	<i>csb_clk/3</i>	Off, <i>csb_clk</i> , <i>csb_clk/2</i> , <i>csb_clk/3</i>
Security core	<i>csb_clk/3</i>	Off, <i>csb_clk</i> , <i>csb_clk/2</i> , <i>csb_clk/3</i>
USB DR, USB MPH	<i>csb_clk/3</i>	Off, <i>csb_clk</i> , <i>csb_clk/2</i> , <i>csb_clk/3</i>
PCI and DMA complex	<i>csb_clk</i>	Off, <i>csb_clk</i>

Table 62. Package Thermal Characteristics for PBGA (continued)

Characteristic	Symbol	Value	Unit	Notes
Junction-to-case thermal	$R_{\theta JC}$	5	°C/W	5
Junction-to-package natural convection on top	Ψ_{JT}	5	°C/W	6

Notes

1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
2. Per SEMI G38-87 and JEDEC JESD51-2 with the single-layer board horizontal.
3. Per JEDEC JESD51-6 with the board horizontal.
4. Thermal resistance between the die and the printed-circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
5. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).
6. Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written as Psi-JT.

20.2 Thermal Management Information

For the following sections, $P_D = (V_{DD} \times I_{DD}) + P_{I/O}$ where $P_{I/O}$ is the power dissipation of the I/O drivers. See [Table 5](#) for I/O power dissipation values.

20.2.1 Estimation of Junction Temperature with Junction-to-Ambient Thermal Resistance

An estimation of the chip junction temperature, T_J , can be obtained from the equation:

$$T_J = T_A + (R_{\theta JA} \times P_D)$$

where:

T_J = junction temperature (°C)

T_A = ambient temperature for the package (°C)

$R_{\theta JA}$ = junction-to-ambient thermal resistance (°C/W)

P_D = power dissipation in the package (W)

The junction-to-ambient thermal resistance is an industry-standard value that provides a quick and easy estimation of thermal performance. Generally, the value obtained on a single-layer board is appropriate for a tightly packed printed-circuit board. The value obtained on the board with the internal planes is usually appropriate if the board has low power dissipation and the components are well separated. Test cases have demonstrated that errors of a factor of two (in the quantity $T_J - T_A$) are possible.

20.2.2 Estimation of Junction Temperature with Junction-to-Board Thermal Resistance

The thermal performance of a device cannot be adequately predicted from the junction-to-ambient thermal resistance. The thermal performance of any component is strongly dependent on the power dissipation of surrounding components. In addition, the ambient temperature varies widely within the application. For

many natural convection and especially closed box applications, the board temperature at the perimeter (edge) of the package is approximately the same as the local air temperature near the device. Specifying the local ambient conditions explicitly as the board temperature provides a more precise description of the local ambient conditions that determine the temperature of the device.

At a known board temperature, the junction temperature is estimated using the following equation:

$$T_J = T_A + (R_{\theta JA} \times P_D)$$

where:

T_J = junction temperature ($^{\circ}\text{C}$)

T_A = ambient temperature for the package ($^{\circ}\text{C}$)

$R_{\theta JA}$ = junction-to-ambient thermal resistance ($^{\circ}\text{C}/\text{W}$)

P_D = power dissipation in the package (W)

When the heat loss from the package case to the air can be ignored, acceptable predictions of junction temperature can be made. The application board should be similar to the thermal test condition: the component is soldered to a board with internal planes.

20.2.3 Experimental Determination of Junction Temperature

To determine the junction temperature of the device in the application after prototypes are available, use the thermal characterization parameter (Ψ_{JT}) to determine the junction temperature and a measure of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} \times P_D)$$

where:

T_J = junction temperature ($^{\circ}\text{C}$)

T_T = thermocouple temperature on top of package ($^{\circ}\text{C}$)

Ψ_{JT} = junction-to-ambient thermal resistance ($^{\circ}\text{C}/\text{W}$)

P_D = power dissipation in the package (W)

The thermal characterization parameter is measured per the JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over about 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

20.2.4 Heat Sinks and Junction-to-Case Thermal Resistance

Some application environments require a heat sink to provide the necessary thermal management of the device. When a heat sink is used, the thermal resistance is expressed as the sum of a junction-to-case thermal resistance and a case-to-ambient thermal resistance:

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CA}$$

Table 64. Heat Sink and Thermal Resistance of MPC8347E (PBGA) (continued)

Heat Sink Assuming Thermal Grease	Air Flow	29 × 29 mm PBGA
		Thermal Resistance
AAVID 30 × 30 × 9.4 mm pin fin	2 m/s	8.8
AAVID 31 × 35 × 23 mm pin fin	Natural convection	11.3
AAVID 31 × 35 × 23 mm pin fin	1 m/s	8.1
AAVID 31 × 35 × 23 mm pin fin	2 m/s	7.5
Wakefield, 53 × 53 × 25 mm pin fin	Natural convection	9.1
Wakefield, 53 × 53 × 25 mm pin fin	1 m/s	7.1
Wakefield, 53 × 53 × 25 mm pin fin	2 m/s	6.5
MEI, 75 × 85 × 12 no adjacent board, extrusion	Natural convection	10.1
MEI, 75 × 85 × 12 no adjacent board, extrusion	1 m/s	7.7
MEI, 75 × 85 × 12 no adjacent board, extrusion	2 m/s	6.6
MEI, 75 × 85 × 12 mm, adjacent board, 40 mm side bypass	1 m/s	6.9

Accurate thermal design requires thermal modeling of the application environment using computational fluid dynamics software which can model both the conduction cooling and the convection cooling of the air moving through the application. Simplified thermal models of the packages can be assembled using the junction-to-case and junction-to-board thermal resistances listed in the thermal resistance table. More detailed thermal models can be made available on request.

Heat sink vendors include the following list:

Aavid Thermalloy 80 Commercial St. Concord, NH 03301 Internet: www.aavidthermalloy.com	603-224-9988
Alpha Novatech 473 Sapena Ct. #12 Santa Clara, CA 95054 Internet: www.alphanovatech.com	408-567-8082
International Electronic Research Corporation (IERC) 413 North Moss St. Burbank, CA 91502 Internet: www.ctscorp.com	818-842-7277
Millennium Electronics (MEI) Loroco Sites 671 East Brokaw Road San Jose, CA 95112 Internet: www.mei-thermal.com	408-436-8770

23 Ordering Information

This section presents ordering information for the device discussed in this document, and it shows an example of how the parts are marked.

NOTE

The information in this document is accurate for revision 1.1 silicon and earlier. For information on revision 3.0 silicon and later versions (orderable part numbers ending with A or B), see the *MPC8347EA PowerQUICC™ II Pro Integrated Host Processor Hardware Specifications* (Document Order No. MPC8347EAEC).

23.1 Part Numbers Fully Addressed by This Document

Table 67 shows an analysis of the Freescale part numbering nomenclature for the MPC8347E. The individual part numbers correspond to a maximum processor core frequency. Each part number also contains a revision code that refers to the die mask revision number. For available frequency configuration parts including extended temperatures, refer to the MPC8347E product summary page on our website listed on the back cover of this document or, contact your local Freescale sales office.

Table 67. Part Numbering Nomenclature

MPC	nnnn	e	t	pp	aa	a	r
Product Code	Part Identifier	Encryption Acceleration	Temperature ¹ Range	Package ²	Processor Frequency ³	Platform Frequency	Revision Level
MPC	8347	Blank = Not included E = included	Blank = 0 to 105°C C = -40 to 105°C	ZU =TBGA VV = PB free TBGA ZQ = PBGA VR = PB Free PBGA	e300 core speed AD = 266 AG = 400 AJ = 533 AL = 667	D = 266 F = 333 ⁴	Blank = 1.1 or 1.0

Notes:

1. For temperature range = C, processor frequency is limited to 400 (PBGA) with a platform frequency of 266 and up to 667(TBGA)with a platform frequency of 333
2. See [Section 18, “Package and Pin Listings,”](#) for more information on available package types.
3. Processor core frequencies supported by parts addressed by this specification only. Not all parts described in this specification support all core frequencies. Additionally, parts addressed by Part Number Specifications may support other maximum core frequencies.
4. ALF marked parts support DDR1 up to 333 MHz (at 333 MHz CSB as the 'F' marking implies) and DDR2 up to 400 MHz (at 200 MHz CSB). AJF marked parts support DDR1 and DDR2 up to 333 MHz (at a CSB of 333 MHz), but DDR2 at 400 MHz (CSB at 200 MHz) is NOT guaranteed.

Table 68 shows the SVR settings by device and package type.

Table 68. SVR Settings

Device	Package	SVR (Rev. 1.0)
MPC8347E	TBGA	8052_0010
MPC8347	TBGA	8053_0010

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